

Notice of References Cited

Application/Control No.

10/573,116

Applicant(s)/Patent Under
Reexamination
HUHSE ET AL.

Examiner

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Art Unit

2877

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	D	US-6,160,626	12-2000	Debeau et al.	356/451
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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